



ALTERNATIVE TO PTO/SB/08a/b (07-05)

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/541,076
				Filing Date	June 29, 2005
				First Named Inventor	Dennis CIPLICKAS
				Art Unit	2825
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	524322000200

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
N.S./	1.	US-5,946,214	08-31-1999	Heavlin et al.	
N.S./	2.	US-6,449,749	09-10-2002	Stine	
N.S./	3.	US-6,985,144	01-10-2006	Chang	
N.S./	4.	US-7,006,947	02-28-2006	Tryon et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
N.S./	5.	WO-05036422	04-21-2005	PDF Solutions, Inc.		

*EXAMINER: Initial if information considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
N.S./	6.	ALLAN, G., (May 2002) "Yield/Reliability Enhancement Using Automated Layout Modifications," 2002 IEEE/SEMI Advanced Semiconductor Manufacturing Conference and Workshop, Boston, MA, pp. 252-261.	

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Examiner Signature	/VuThe Siek/ (01/03/2008)	Date Considered	
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